

Notice of References Cited	Application/Control No. 10/646,623	Applicant(s)/Patent Under Reexamination NAITOH ET AL.	
	Examiner Rick K. Chang	Art Unit 3729	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,192,580 B1	02-2001	Hayami, Keiko	29/846
	B	US-5,317,801 A	06-1994	Tanaka et al.	29/830
	C	US-4,325,780	04-1982	Schulz, Sr., Robert M.	216/17
	D	US-6,228,511 B1	05-2001	Sachdev et al.	428/626
	E	US-5,502,893 A	04-1996	Endoh et al.	29/852
	F	US-6,684,497 B2	02-2004	Appelt et al.	29/852
	G	US-6,591,495 B2	07-2003	Hirose et al.	29/846
	H	US-6,323,439 B1	11-2001	Kambe et al.	174/262
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.